

Notice of References Cited

Application/Control No.

10/804,405

Applicant(s)/Patent Under
Reexamination
LIU ET AL.

Examiner

Todd Ingberg

Art Unit

2193

Page 1 of 3

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	Examiner Todd Ingberg	Art Unit 2193	Page 2 of 3

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Page 3 of 3

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